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AMENDMENTS TO THE CLAIMS

Please cancel claims 9-13 without prejudice or disclaimer, add claims 22-27, amend claims 1, 4, 8, 14, 16, and 19-21 as follows:

1. (Currently Amended) A method of controlling a conductivity of a Ga₂O₃ system single crystal, comprising:

adding a predetermined dopant to the Ga₂O₃ system single crystal such that said dopant is substituted for Ga in the Ga₂O₃ system single crystal to obtain a desired conductivity,

wherein said predetermined dopant comprises one of:

an n-type dopant for controlling said conductivity of the Ga₂O₃ system single crystal comprising one of Si, Hf, Ge, Sn, and Ti, said conductivity of the Ga₂O₃ system single crystal being controlled depending on an adding amount of said n-type dopant; and

a p-type dopant for controlling said conductivity of the Ga₂O₃ system single crystal comprising one of H, Li, Na, K, Rb, Cs, Fr, Be, Ca, Sr, Ba, Ra, Mn, Fe, Co, Ni, Pd, Cu, Ag, Au, Zn, Cd, Hg, Tl, and Pb, said conductivity of the Ga₂O₃ system single crystal being controlled depending on an adding amount of said p-type dopant, and

wherein a purity of said Ga₂O₃ system single crystal is 6N.

2. - 3. (Canceled).

4. (Currently Amended) The method of controlling a conductivity of a Ga_2O_3 system single crystal according to claim 1, wherein a value of 2.0 X 10^{-3} to 8.0 X 10^2 Ω cm is obtained as the <u>a</u> desired resistivity by adding a predetermined amount of said n-type dopant.

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5. (Previously Presented) The method of controlling a conductivity of a Ga_2O_3 system single crystal according to claim 4, wherein a carrier concentration of the Ga_2O_3 system single crystal is controlled to fall within a range of 5.5 X 10^{15} to 2.0 X 10^{19} /cm³ as a range of the desired resistivity.

6.-7. (Cancelled).

- 8. (Currently Amended) The method of controlling a conductivity of a Ga_2O_3 system single crystal according to claim 1, wherein 1 X $10^3 \Omega$ cm or more is obtained as the <u>a</u> desired resistivity by adding a predetermined amount of said p-type dopant.
- 9.-13. (Canceled).
- 14. (Withdrawn Currently Amended) A light emitting element, comprising:

an n-type β -AlGaO₃ cladding layer, an active layer, a p-type β -AlGaO₃ cladding layer, and a p-type β -Ga₂O₃ contact layer respectively laminated in order on an n-type β -Ga₂O₃ contact layer, said n-type β -Ga₂O₃ contact layer made of a β -Ga₂O₃ single crystal;

a transparent electrode and a pad electrode respectively formed in order on said p-type β - Ga_2O_3 contact layer; and

an n-side electrode formed over a lower surface of said n-type β -Ga₂O₃ contact layer, wherein a desired resistivity of said β -Ga₂O₃ single crystal is obtained,

wherein a purity of said β-Ga₂O₃ single crystal is 6N,

wherein said n-type layers comprise a dopant including one of Si, Hf, Ge, Sn, and Ti, and wherein said p-type layers comprise a dopant including one of H, Li, Na, K, Rb, Cs, Fr, Be, Ca, Sr, Ba, Ra, Mn, Fe, Co, Ni, Pd, Cu, Ag, Au, Zn, Cd, Hg, Tl, and Rb.

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15. (Withdrawn) The light emitting element of claim 14, wherein a carrier concentration of said p-type β -Ga₂O₃ contact layer is greater than that of said p-type β -AlGaO₃ cladding layer; and

wherein a carrier concentration of said n-type β -Ga₂O₃ contact layer is greater than that of said n-type β -AlGaO₃ cladding layer.

16. (Currently Amended) A method of controlling a conductivity of a Ga₂O₃ system single crystal, comprising:

adding a predetermined dopant to the Ga₂O₃ system single crystal such that said dopant is substituted for Ga in the Ga₂O₃ system single crystal to obtain a desired conductivity,

wherein said predetermined dopant comprises a p-type dopant for controlling said conductivity of the Ga₂O₃ system single crystal, said p-type dopant comprising one of H, Li, Na, K, Rb, Cs, Fr, Be, Mg, Ca, Sr, Ba, Ra, Mn, Fe, Co, Ni, Pd, Cu, Ag, Au, Zn, Cd, Hg, Tl, and Pb, said conductivity of the Ga₂O₃ system single crystal being controlled depending on an adding amount of said p-type dopant, and

wherein a purity of said Ga₂O₃ system single crystal is 6N.

- 17. (Previously Presented) The method of controlling said conductivity of said Ga₂O₃ system single crystal according to claim 16, wherein the predetermined dopant comprises one of: said p-type dopant; and an n-type dopant for controlling said conductivity of the Ga₂O₃ system single crystal.
- 18. (Previously Presented) The method of controlling a conductivity of a Ga₂O₃ system single crystal according to claim 17, wherein said n-type dopant comprises one of Si, Hf, Ge, Sn, Ti, and Zr.

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19. (Currently Amended) The method of controlling a conductivity of a Ga_2O_3 system single crystal according to claim 17, wherein a value of 2.0 X 10^{-3} to 8.0 X 10^2 Ω cm is obtained as the <u>a</u> desired resistivity by adding a predetermined amount of said n-type dopant.

- 20. (Currently Amended) The method of forming a Ga_2O_3 system single crystal layer according to claim 19, wherein a carrier concentration of the Ga_2O_3 system single crystal is controlled to fall within a range of 5.5 X 10^{15} to 2.0 X 10^{19} /cm³ as a range of said <u>desired</u> resistivity.
- 21. (Currently Amended) The method of controlling a conductivity of a Ga_2O_3 system single crystal according to claim 16, wherein 1 X 10^3 Ω cm or more is obtained as the <u>a</u> desired resistivity by adding a predetermined amount of said p-type dopant.
- 22. (New) A method of controlling a conductivity of a Ga₂O₃ system single crystal, comprising: adding a predetermined dopant to the Ga₂O₃ system single crystal such that said predetermined dopant is substituted for Ga in the Ga₂O₃ system single crystal to obtain a desired conductivity,

wherein said predetermined dopant comprises a p-type dopant for controlling said conductivity of the Ga₂O₃ system single crystal, said p-type dopant comprising one of H, Li, Na, K, Rb, Cs, Fr, Be, Mg, Ca, Sr, Ba, Ra, Mn, Fe, Co, Ni, Pd, Cu, Ag, Au, Zn, Cd, Hg, Tl, and Pb, said conductivity of the Ga₂O₃ system single crystal being controlled depending on an adding amount of said p-type dopant,

wherein said desired conductivity is dependent upon an amount of said predetermined dopant added to said Ga₂O₃ system single crystal.

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23. (New) The method of controlling said conductivity of said Ga₂O₃ system single crystal according to claim 22, wherein the predetermined dopant comprises one of:

said p-type dopant; and

an n-type dopant for controlling said conductivity of the Ga₂O₃ system single crystal.

- 24. (New) The method of controlling a conductivity of a Ga₂O₃ system single crystal according to claim 23, wherein said n-type dopant comprises one of Si, Hf, Ge, Sn, Ti, and Zr.
- 25. (Currently Amended) The method of controlling a conductivity of a Ga_2O_3 system single crystal according to claim 23, wherein a value of 2.0 X 10^{-3} to 8.0 X 10^2 Ω cm is obtained as a desired resistivity by adding a predetermined amount of said n-type dopant.
- 26. (New) The method of forming a Ga_2O_3 system single crystal layer according to claim 25, wherein a carrier concentration of the Ga_2O_3 system single crystal is controlled to fall within a range of 5.5 X 10^{15} to 2.0 X 10^{19} /cm³ as a range of said desired resistivity.
- 27. (New) The method of controlling a conductivity of a Ga_2O_3 system single crystal according to claim 22, wherein 1 X 10^3 Ω cm or more is obtained as a desired resistivity by adding a predetermined amount of said p-type dopant.